

**ABSTRACT OF THE DISCLOSURE**

A method is proposed for carrying out quality control on an analytical process which belongs to a group of related analytical processes that can be executed in at least one analytical device and includes a respective chain of sub-processes. The method includes fundamental chemical and/or physical underlying sub-processes being stored for the group in a first database. Further, at least one section of the chain of the analytical process is emulated by the specification of one of the underlying sub-processes for each sub-process in a section of the chain, using at least one control parameter and at least one corresponding threshold value. Finally, measured values are determined for the control parameters for at least one run of the analytical process and the measured values are compared with the corresponding threshold values for the quality control procedure.